

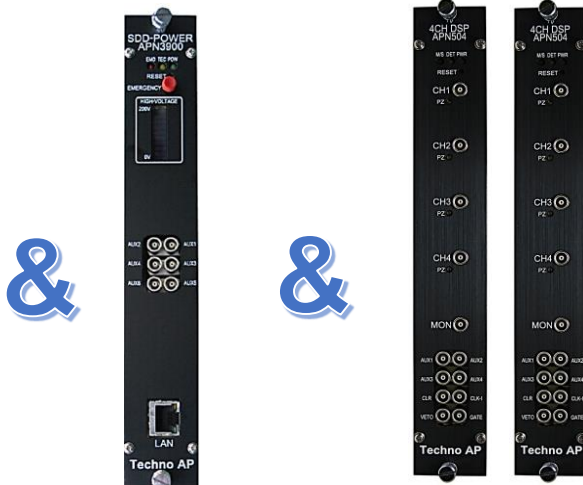
## XSDDD50-07BE-SYS

A silicon drift detector (SDD), a data measurement board, and a power supply for the detector, which are necessary for X-ray absorption fine structure measurement used for structural analysis in the materials field, are all in one package. **The silicon drift detector, which has high counting rate and energy resolution, is multi-element to realize high sensitivity.** In addition, transistor reset processing and DSP processing are performed appropriately to enable high-counting measurement.

- **Sensitive area: 350mm<sup>2</sup>**  
collimated to 50mm<sup>2</sup> x 7-element
- **Element area: 455mm<sup>2</sup>**  
65mm<sup>2</sup> x 7-element



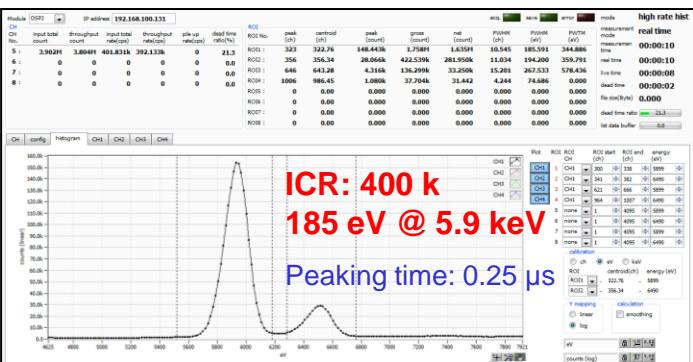
**SDD with Beryllium window**  
Model: XSDDD50-07BE  
1 pc



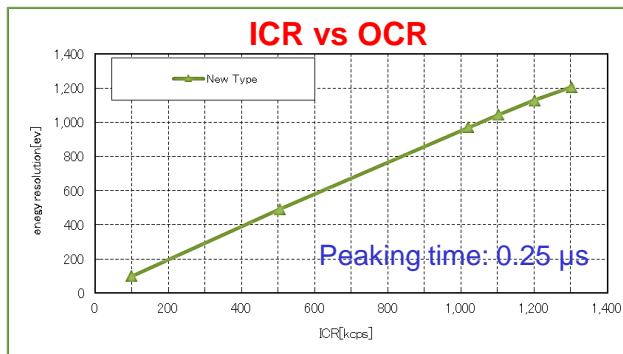
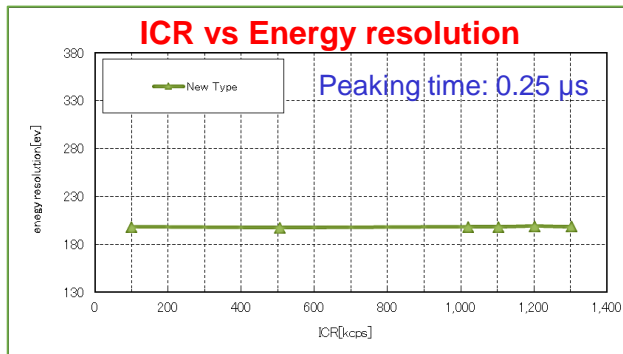
**Power supply for SDD**  
NIM type  
Model: APN3900  
1 pc

**DSP for SDD**  
NIM type  
Model: APN504X  
2 pcs

\*NIM bin power supply required



Application window for data collection



### Specifications

Functions	Histogram, List, Waveform, ROI-SCA
Energy resolution	244 eV @5.9 keV MnKa (OCR: 1000 k, Peaking time: 0.25μs)
ADC	100 MHz, 16-bit
Power supply for SDD	-200V, ±5V, + 3.3V
Communication I/F	Gigabit ethernet, TCP/IP
Accessories	Application for data acquisition, Sample program, Instruction Manual

\*Images is for illustration purpose.  
\*Please note that contents may change without prior notice.

